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| Notice of References Cited | Application/Control No. 10/522,481 | Applicant(s)/Patent Under Reexamination CHA ET AL. | |
| | Examiner John D. Lee <i>John D. Lee</i> | Art Unit 2874 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| * | A | US-5,583,681 | 12-1996 | Shioya et al. | 349/60 |
| * | B | US-5,808,707 | 09-1998 | Niibori et al. | 349/60 |
| * | C | US-6,067,133 | 05-2000 | Niibori et al. | 349/60 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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